## **AMENDMENTS TO THE SPECIFICATION**

Please rewrite the paragraph on page 1, lines 6-10, to read as follows:

## -- BACKGROUND OF THE INVENTION

The invention relates to a measuring device for impedance spectroscopy of particles which are suspended in a carrier liquid, according to the precharacterizing part of claim 1, as well as to a corresponding measuring method according to the pre-characterizing part of claim 39.

Please rewrite the paragraph on page 1, lines 27-31, to read as follows:

## -- SUMMARY OF THE INVENTION

Starting with a known measuring device for impedance spec-tros-copy, this objective is met, according to the pre-characterizing part of claim 1, by the characterizing features of claim 1 and in relation to a corresponding measuring method - by the characteristics of claim 39. --

Please rewrite the paragraph on page 11, lines 20-24, to read as follows:

## -- BRIEF DESCRIPTION OF SEVERAL VIEWS OF THE DRAWINGS

Other advantageous improvements of the invention are characterized in the subordinate claims or result from the following description of the preferred embodiments of the invention in conjunction with the drawings. The following are shown: --

Please add on page 13, line 16, the following heading:

-- DETAILED DESCRIPTION OF PREFERRED EMBODIMENTS --